



~~IN THE UNITED STATES PATENT AND TRADEMARK OFFICE~~

28/7/7

In re Applicant:

Ofer DU-NOUR

Serial No.: 09/762,473

Filed: February 7, 2001

Group Art Unit: 2877

For: Method and Apparatus for Measuring the Thickness of a Transparent Film, Particularly of a Photoresist Film on a Semiconductor Substrate

Attorney
Docket: **24982**
Previously 1639/14

Examiner: Samuel A. Turner

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

PETITION AND FEE FOR EXTENSION OF TIME UNDER 37 CFR 1.136(a)

Sir:

Respectfully submitted,

Sol Sheinbein
Registration No. 25,457

Date: February 18, 2004

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